Notice of References Cited Application/Control No. 10/708,838 Examiner Daniel I. Walsh Applicant(s)/Patent Under Reexamination BEENAU ET AL. Page 1 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,245,329	09-1993	Gokcebay, Asil T.	340/5.33
	В	US-5,677,953	10-1997	Dolphin, Janet L.	705/51
	С	US-5,869,822	02-1999	Meadows et al.	235/380
	D	US-5,987,155	11-1999	Dunn et al.	382/116
	E	US-6,268,788	07-2001	Gray, Robert J.	340/5.2
	F	US-6,269,348	07-2001	Pare et al.	705/39
	G	US-2001/0053239	12-2001	Takhar, Harinder S.	382/124
	H	US-2002/0062249	05-2002	lannacci, Gregory Fx	705/14
	1	US-2002/0062284	05-2002	KAWAN, JOSEPH C:	705/43
	J	US-2002/0066784	06-2002	Segal et al.	235/381
	К	US-2002/0095587	07-2002	Doyle et al.	713/186
	L	US-2002/0097142	07-2002	Janiak et al.	340/5.53
	М	US-2002/0140542	10-2002	Prokoski et al.	340/5.52

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	σ					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 10/708,838 Examiner Daniel I. Walsh Applicant(s)/Patent Under Reexamination BEENAU ET AL. Page 2 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0163421	11-2002	Wang et al.	340/5.83
	В	US-2002/0178063	11-2002	Gravelle et al.	705/17
	С	US-2002/0191816	12-2002	Maritzen et al.	382/115
	D	US-2003/0086591	05-2003	Simon, Rudy	382/115
	Е	US-2003/0112120	06-2003	K., Seifert Mark	340/5.53
	F	US-2003/0149661	08-2003	Mitchell et al.	705/39
	G	US-2003/0150911	08-2003	Joseph, Joseph	235/382
	Н	US-2003/0226041	12-2003	Palmer et al.	713/202
	1	US-2003/0229793	12-2003	McCall et al.	713/186
	J	US-2004/0020982	02-2004	Hoffman et al.	235/379
	к	US-2004/0021552	02-2004	Koo, Hong-Sik	340/5.53
	L	US-2004/0041021	03-2004	Nugent, Paul F. JR.	235/383
	М	US-2004/0041690	03-2004	Yamagishi, Junichi	340/005.52

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Ρ					
	a					
	R					
	S					
	٢					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 10/708,838 Examiner Daniel I. Walsh Applicant(s)/Patent Under Reexamination BEENAU ET AL. Page 3 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0084542	05-2004	DeYoe et al.	236/049.3
	В	US-2004/0131237	07-2004	Machida, Akihiro	- 382/124
	С	US-2004/0133787	07-2004	Doughty et al.	713/186
	D	US-2004/0149827	08-2004	Zuili, Patrick	235/439
	E	US-2004/0155101	08-2004	Royer et al.	235/379
	F	US-2004/0195314	10-2004	Lee, Ki Deak	235/380
	G	US-2004/0199469	10-2004	Barillova et al.	705/044
	Н	US-2004/0208343	10-2004	Golden et al.	382/110
	1	US-2004/0257196	12-2004	Kotzin, Michael D.	340/005.52
	J	US-2005/0001711	01-2005	Doughty et al.	340/005.74
	К	US-2005/0005172	01-2005	Haala, Catherine A.	713/202
	L	US-2005/0018658	01-2005	Ikeda et al.	370/352
	М	US-2005/0033992	02-2005	Inabe, Takeshi	713/202

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ņ			•		
	0					
	Ρ					
	ø					
	R					
	ø					
	Т					

NON-PATENT DOCUMENTS

_		
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYYY format are publication dates. Classifications may be US or foreign.

Application/Control No. Applicant(s)/Patent Under Reexamination 10/708,838 BEENAU ET AL. Notice of References Cited Examiner Art Unit Page 4 of 4 Daniel I. Walsh 2876

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2005/0054438	03-2005	Rothschild et al.	463/029
	В	US-2005/0065872	03-2005	Moebs et al.	705/038
	С	US-2005/0087597	04-2005	Gotfried et al.	235/382
	D	US-2005/0091325	04-2005	Kuwana et al.	709/206
	Ε	US-2005/0102524	05-2005	Haala, Catherine A.	713/186
	F	US-2005/0122209	06-2005	Black, Gerald R.	340/005.52
	G	US-2005/0139669	06-2005	Arnouse, Michael	235/440
	Н	US-			
	_	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	σ					
	R					
	s		·			
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.